

REPLACEMENT SHEETS



09/871739

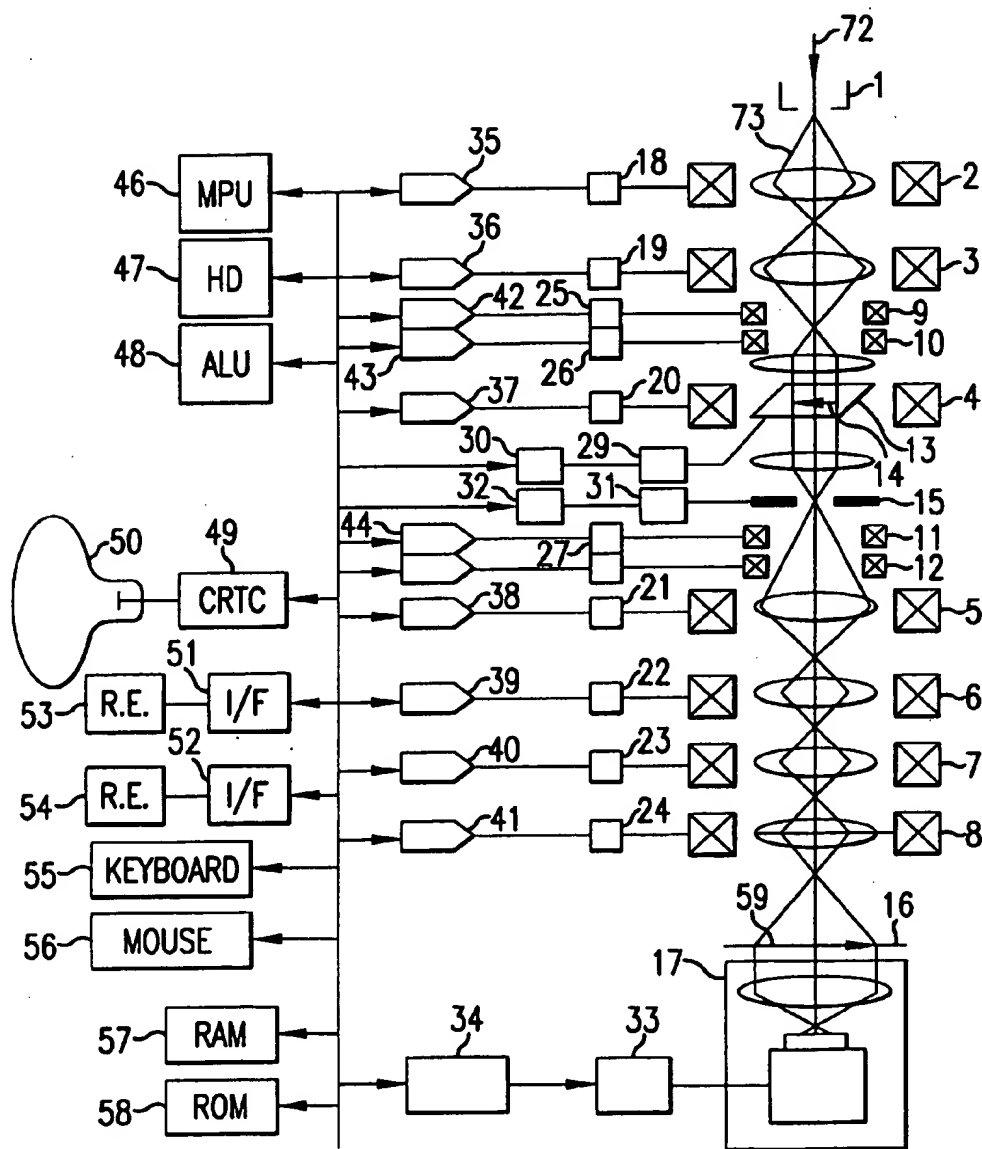


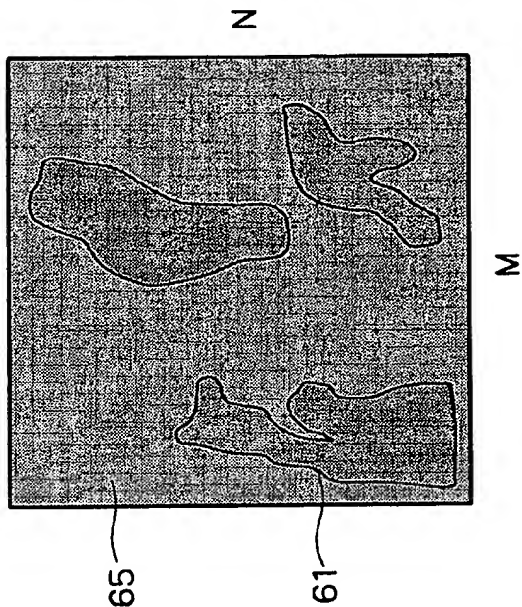
FIG. 1

Figure 1 is a schematic diagram of an image processing system for defect detection. The main image is divided into a grid of fields. A "REGION TO BE SEARCHED" is highlighted in a circular area. A "MAGNIFIED STRUCTURE" is shown as a detailed view of a specific region. Three inset images are shown: (A) IMAGE IN FIELD 1, (B) IMAGE IN FIELD 5, and (C) IMAGE IN FIELD 9. A "BREAKAGE OF SAMPLE" is indicated by a line across the grid. The grid is labeled with numbers 1 through 9. The main image is labeled with 6, 61, 62, and 64. A coordinate system (x, y) is shown at the bottom right.



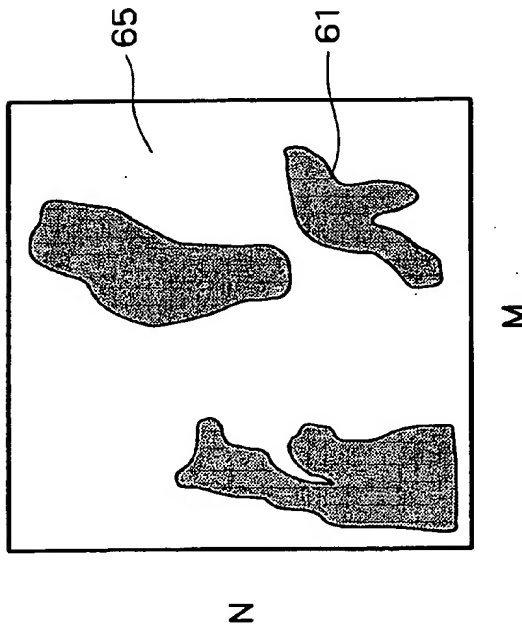
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FIG. 3B



EXAMPLE OF MAGNIFIED
SAMPLE TRANSMISSION
IMAGE (LOW CONTRAST)

FIG. 3A



EXAMPLE OF MAGNIFIED
SAMPLE TRANSMISSION IMAGE



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FIG. 4

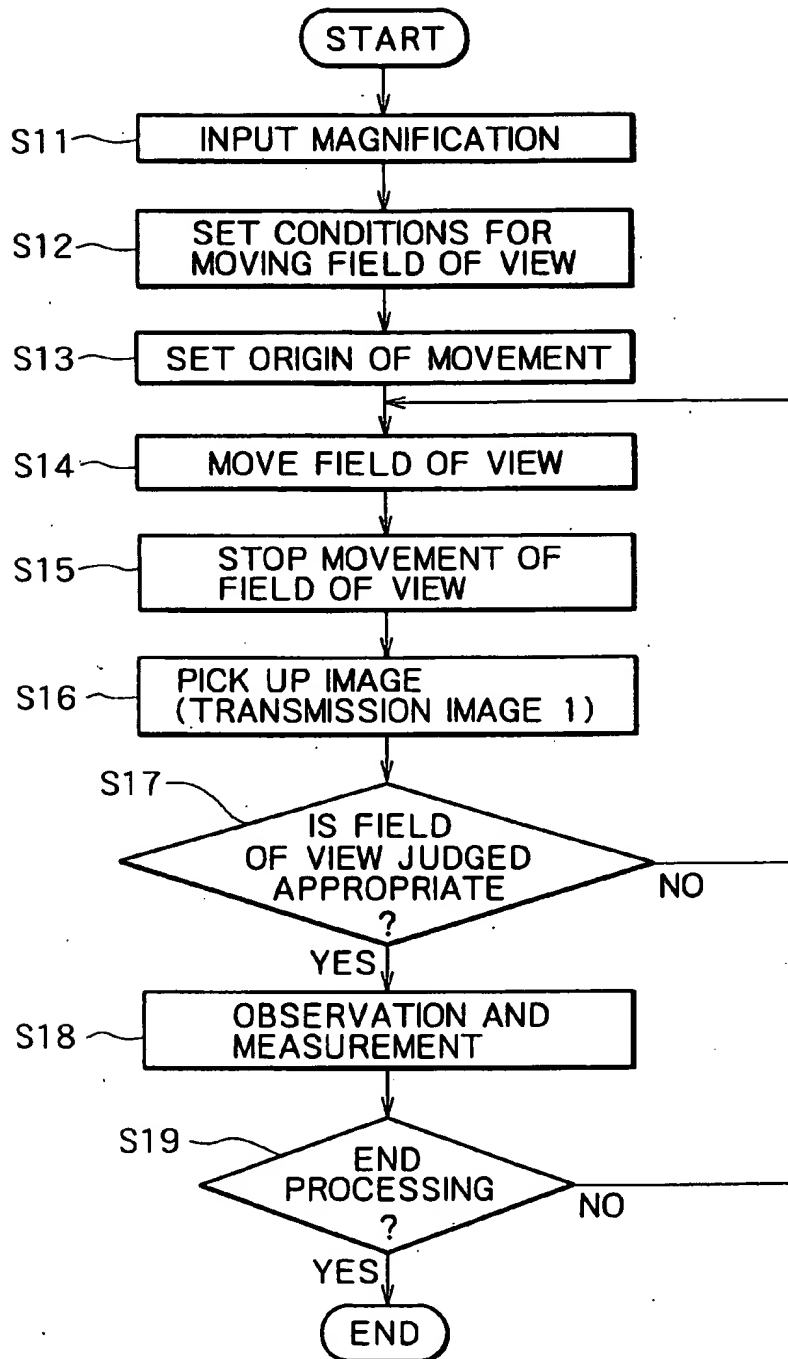
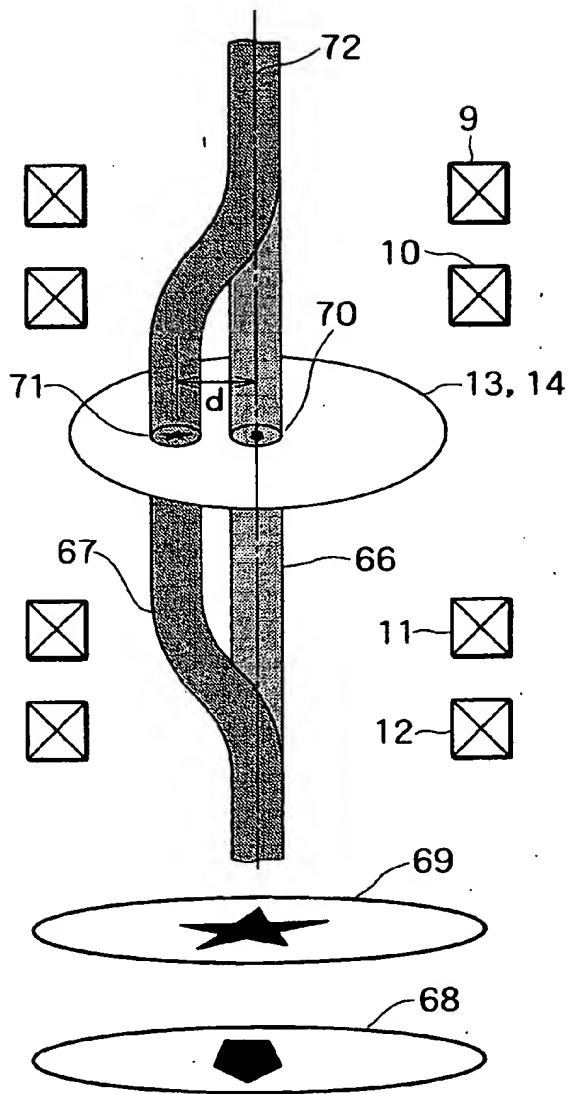
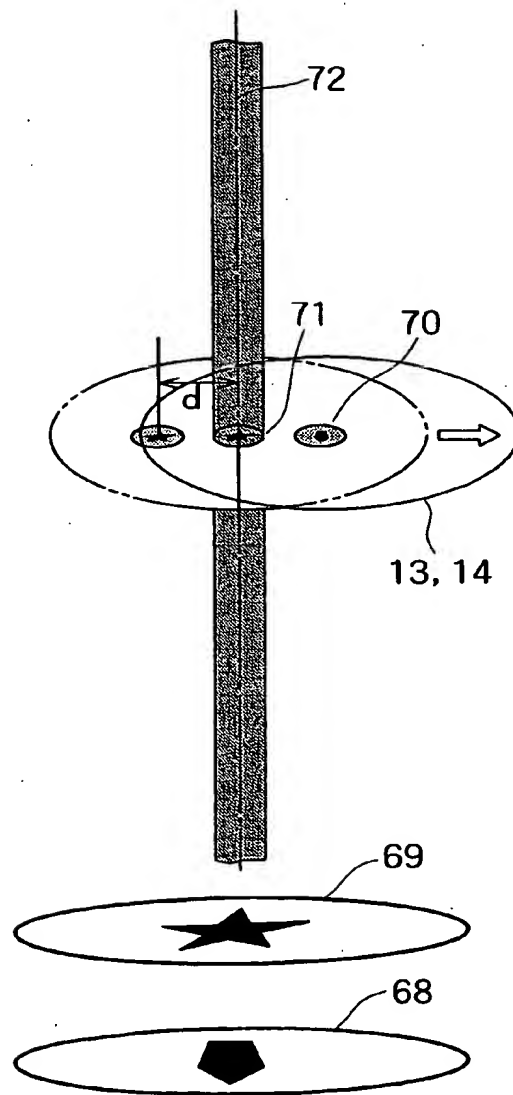


FIG. 5A



ELECTROMAGNETIC
 MOVEMENT OF FIELD OF
 VIEW USING ELECTRON
 BEAM DEFLECTING COIL

FIG. 5B



MECHANICAL MOVEMENT
 OF FIELD OF VIEW USING
 SAMPLE STAGE DRIVER



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FIG. 6A

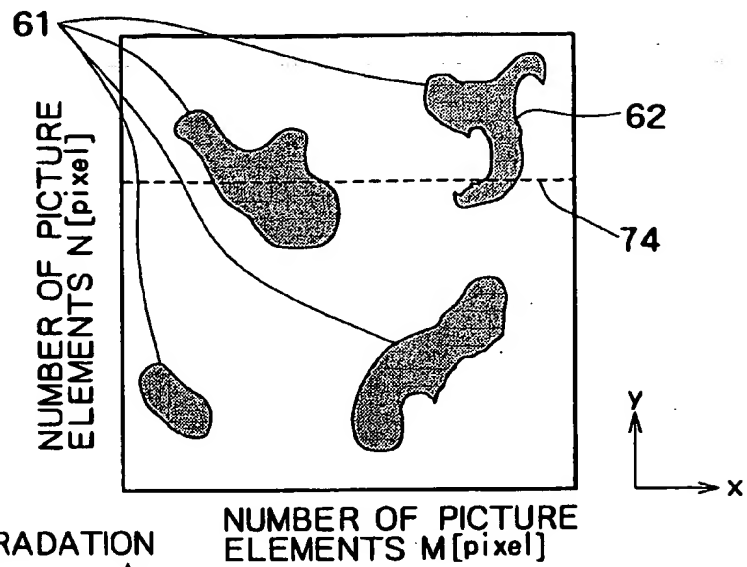


FIG. 6B

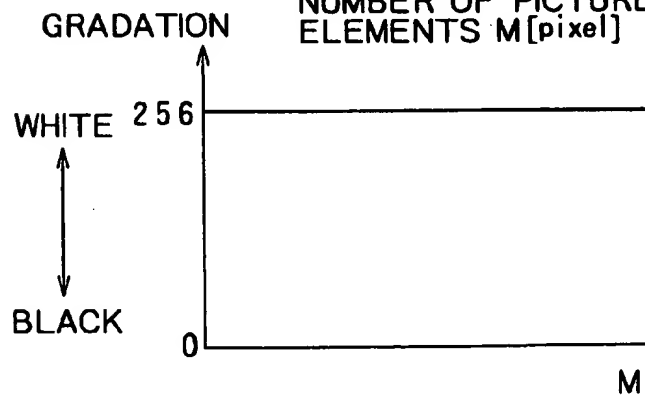


FIG. 6C

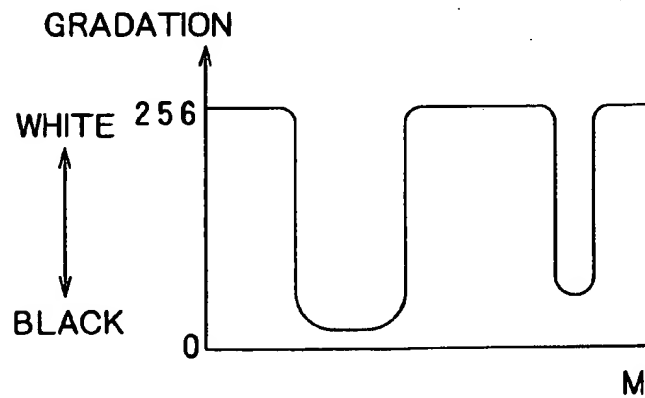
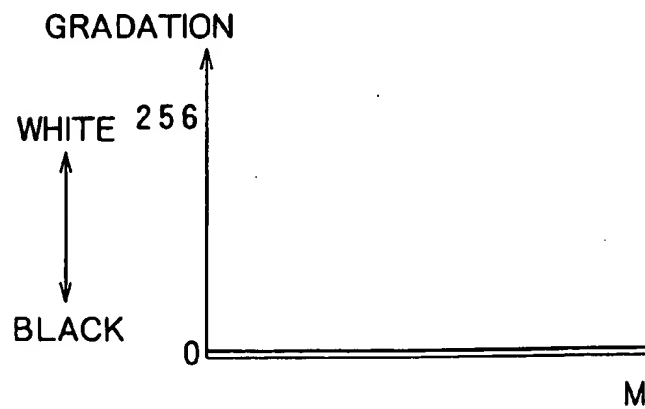
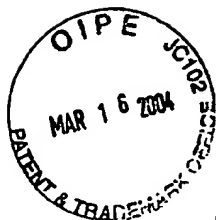


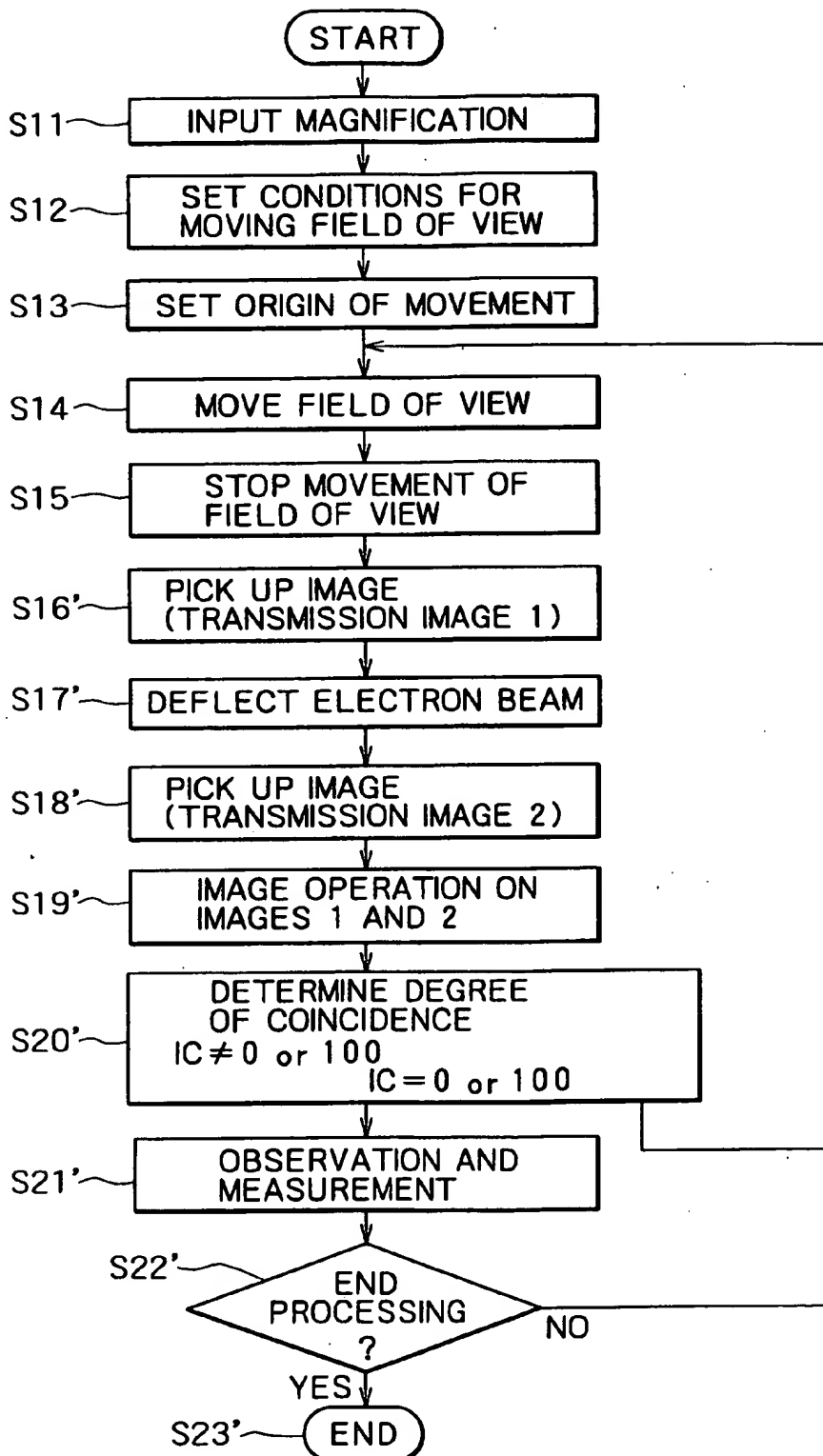
FIG. 6D





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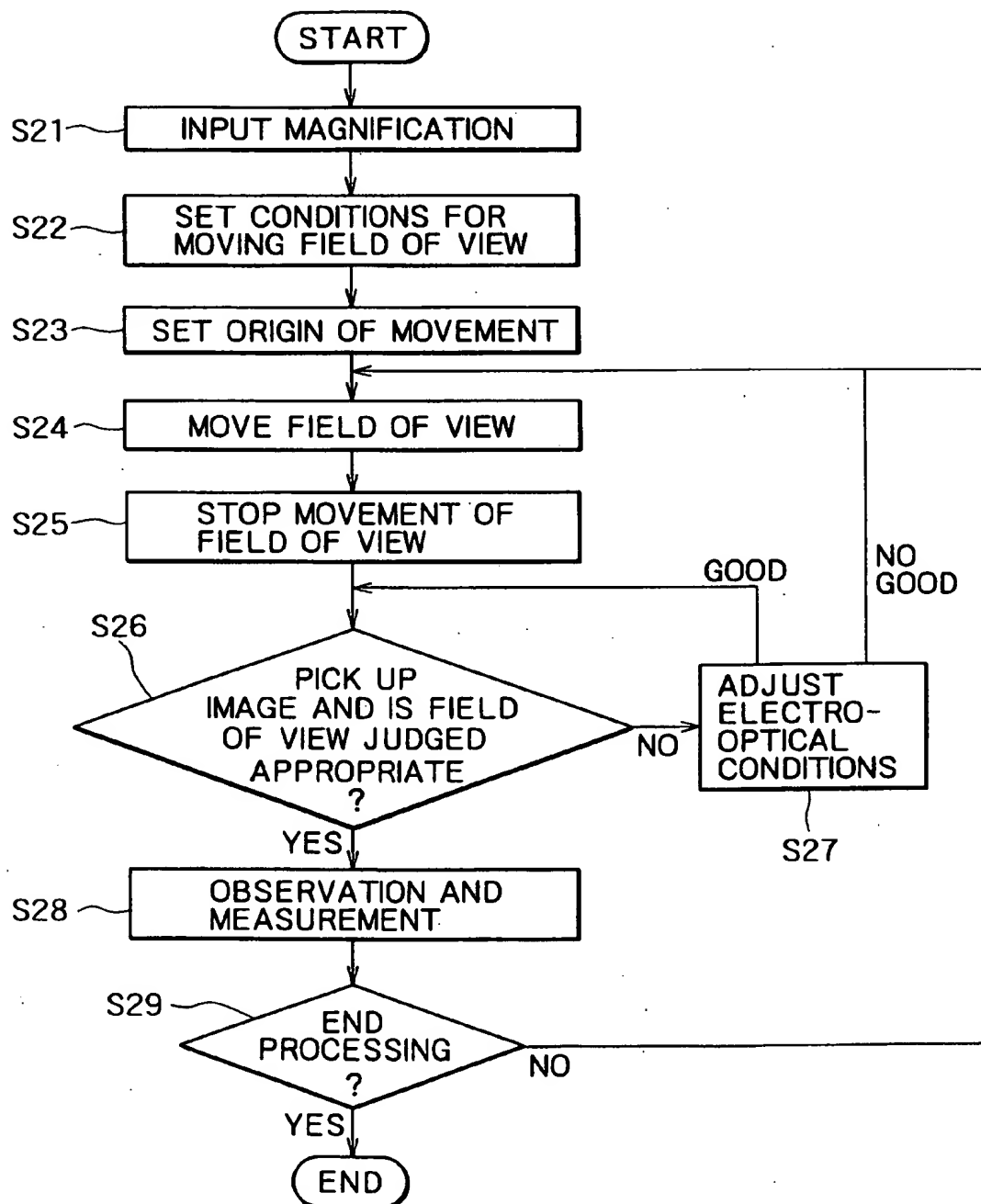
FIG. 7





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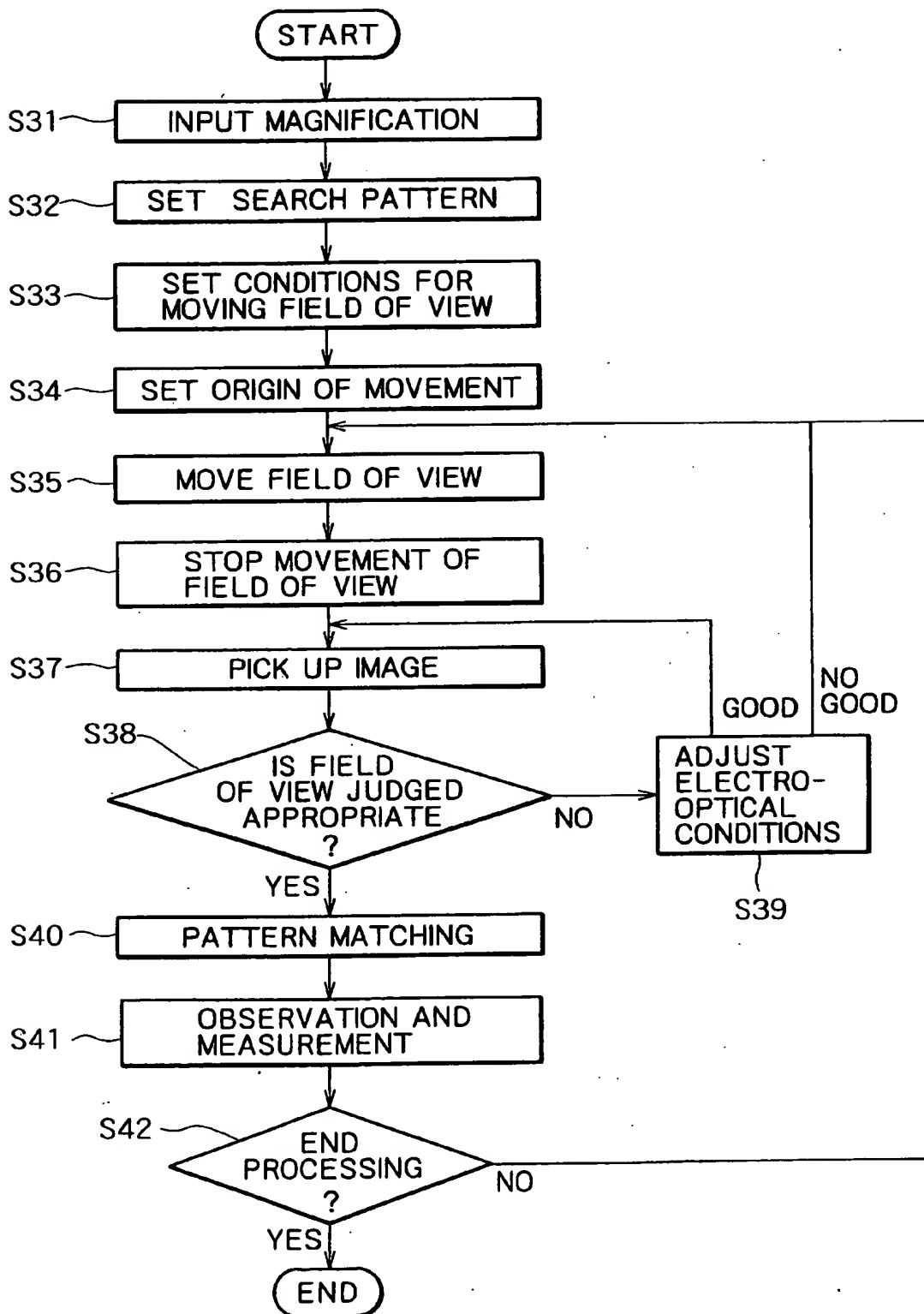
FIG. 8





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FIG. 9

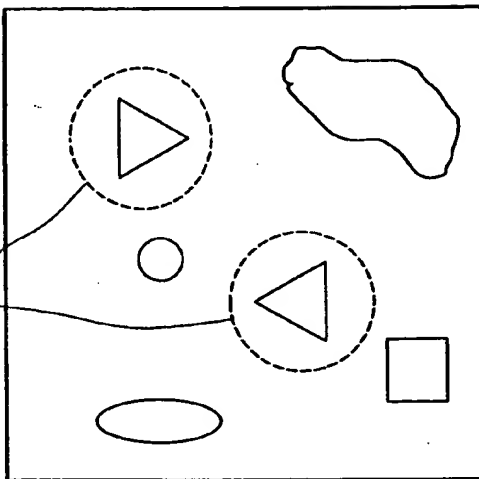




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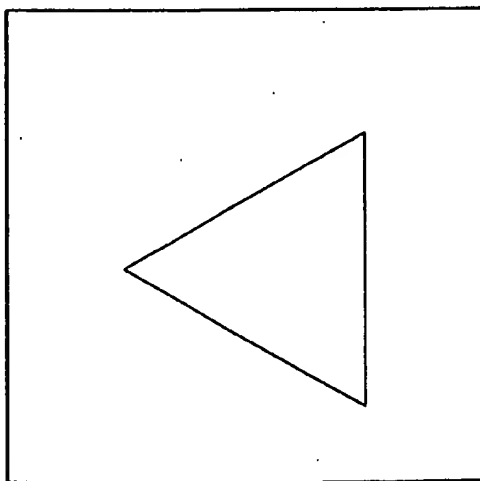
FIG. 10B

SEARCH SAMPLE
(MARKING)

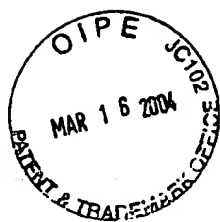


PICKED-UP FIELD OF VIEW
NUMBER OF SEARCH
SAMPLES=2

FIG. 10A

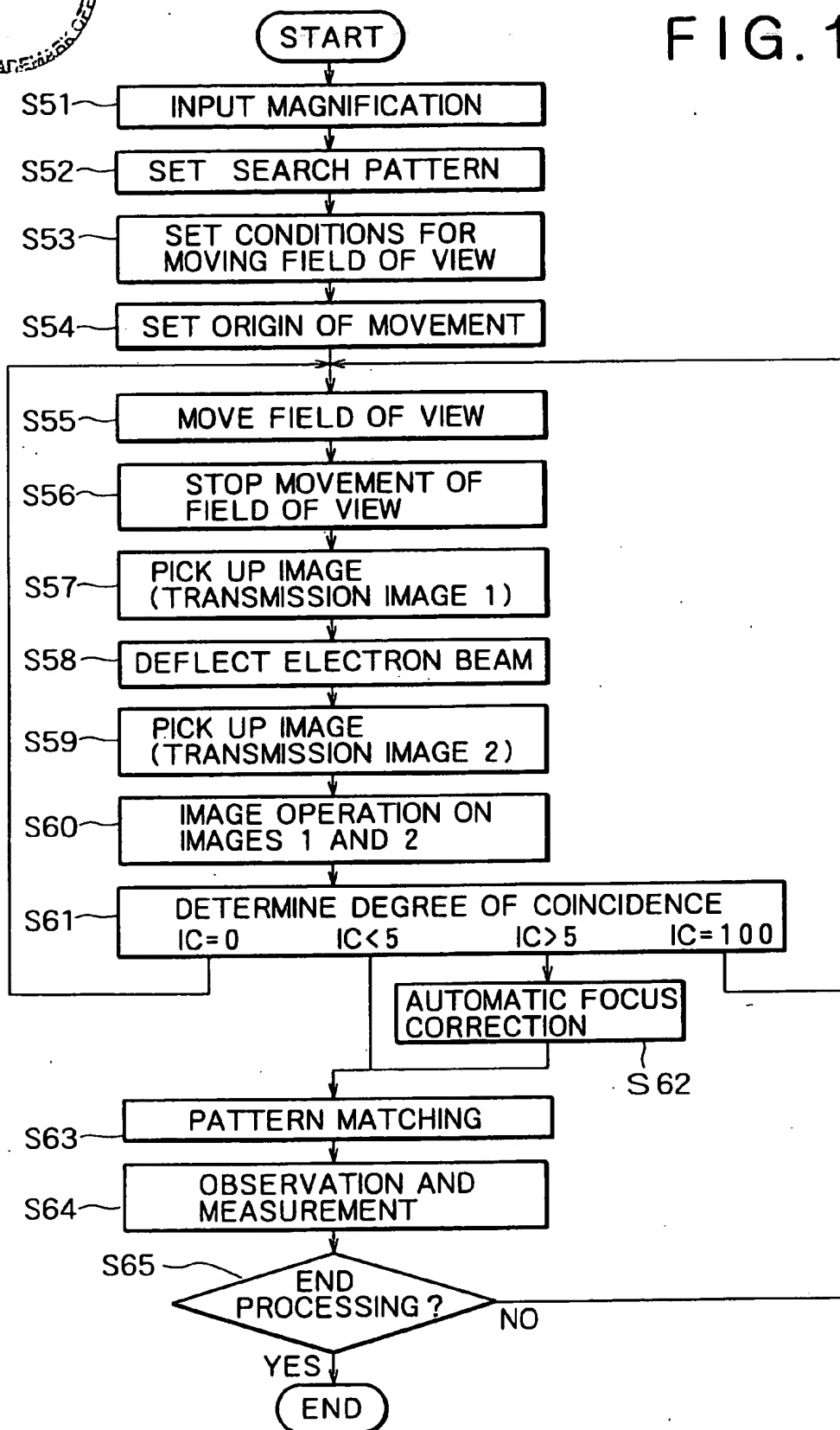


SEARCH TARGET
PATTERN



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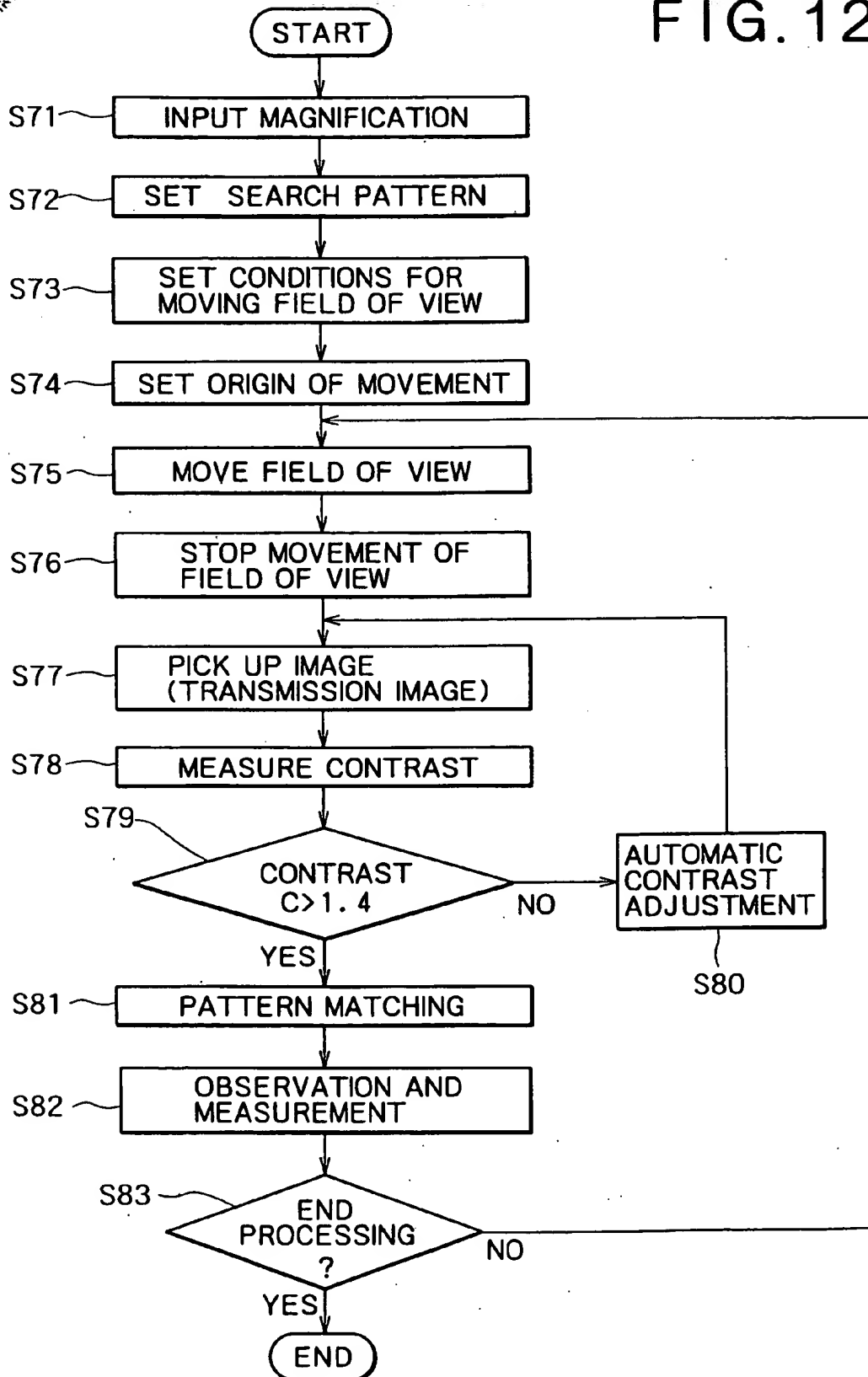
FIG. 11





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FIG. 12





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FIG. 13 (1)

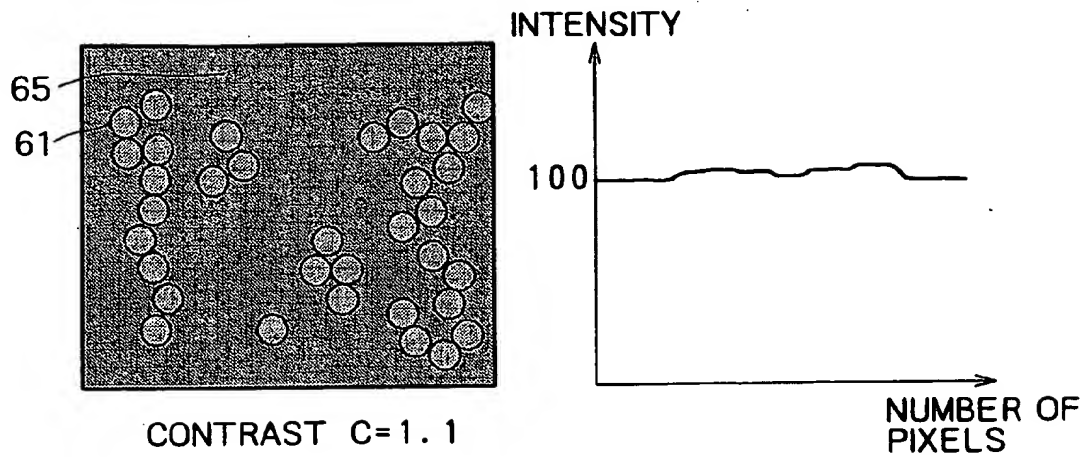


FIG. 13 (2)

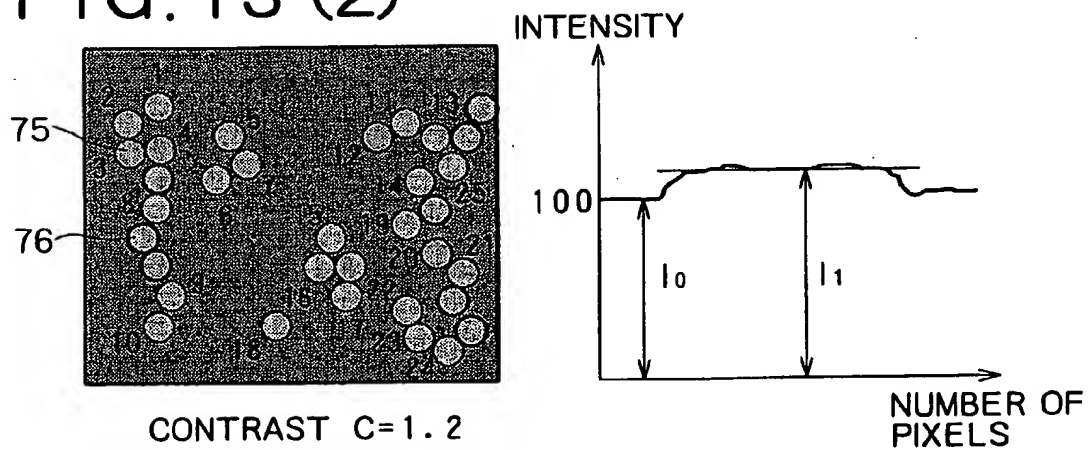
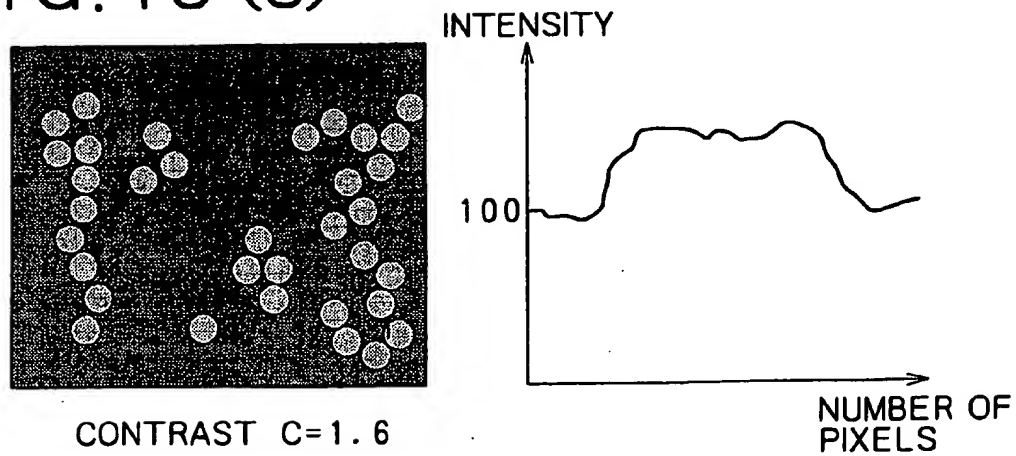


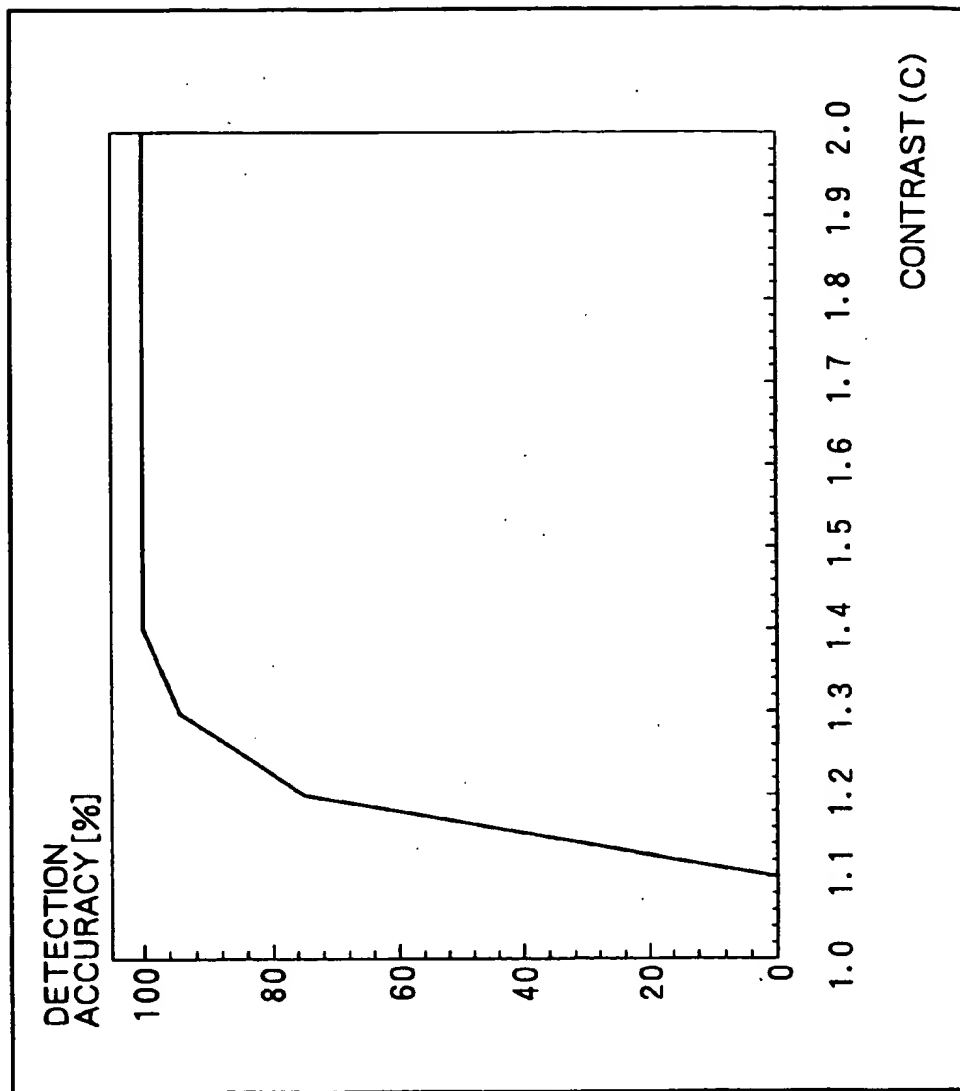
FIG. 13 (3)





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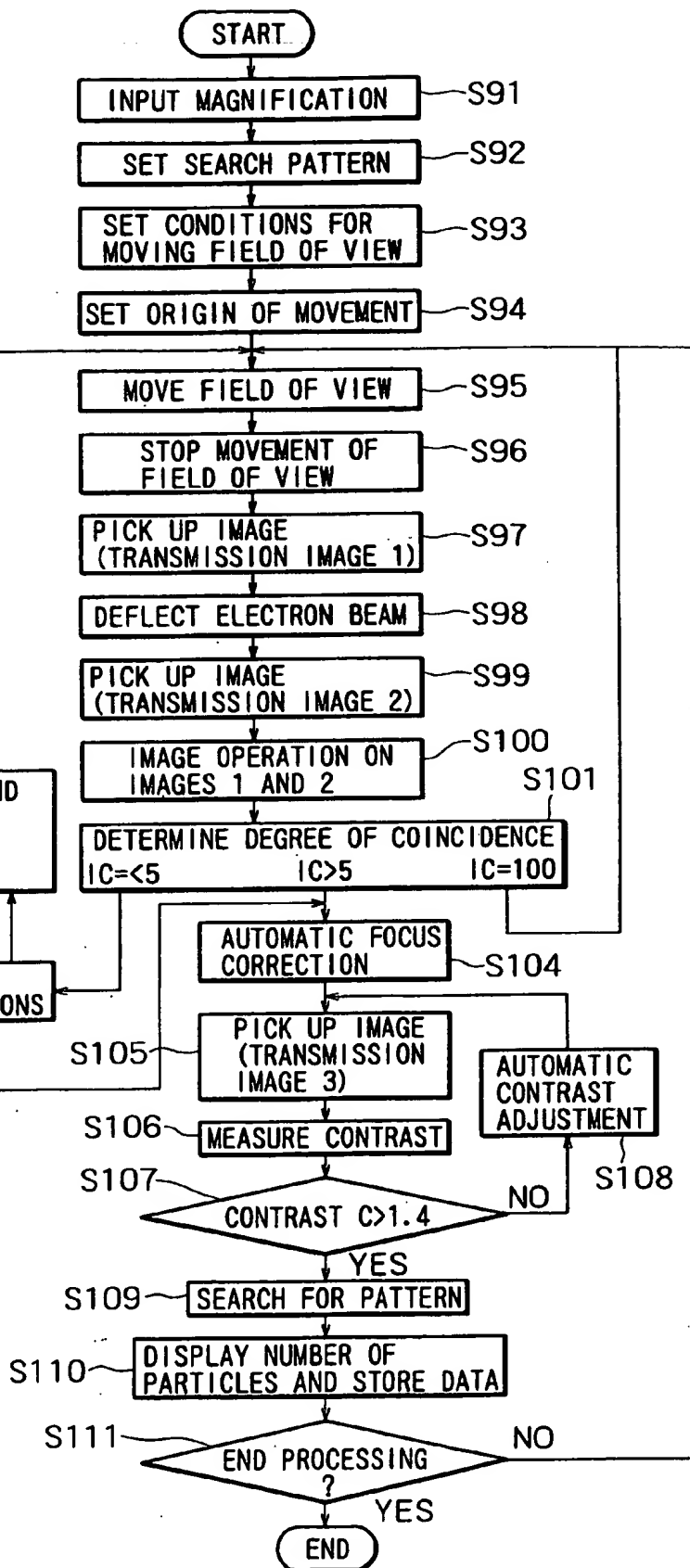
FIG. 14





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FIG. 15





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FIG. 16

